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The experimental validation of radiation damage modeling

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The experimental validation of radiation damage modeling

II. The initial attempts to multiscale

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Electron microscopy: ED nc Ni



Sample A, <111>, 21.3nm



Sample B, <200>, 20.4 nm

Electron microscopy:HPT nc Ni





Microstructure of HPT nc Ni: a) \rightarrow c) Dislocations and subgrains change in microstrains with the thickness of the specimen

in HPT nc Ni

Two synthesis methods produce different grain size distributions



Ni⁺ ion irradiation conditions (TRIM)



The microstructure of HPT Ni



unirradiated

irradiated, 0.5 dpa p⁺

Microstructure ED nc Ni



irradiated with Ni⁺ ions to 5 dpa SFT density 5.9x10²² m⁻³

B = <110> and g=<002>.

Microstructure of irradiated HPT Ni



 $B = \langle 110 \rangle$ and $g = \{002\}$. SFT mean size: 2.5 nm, density 7.4x10²² m⁻³

Grain size distribution of both unirradiated and irradiated HPT Ni



Average grain size decreases from 115 nm (unirradiated, 34 nm by XRD) to 38 nm (irradiated)

Defect accumulation after irradiation



Irradiation induced defect clusters in Cu (4.6 10⁻² dpa) and Pd (6.6 10⁻² dpa)





The fcc structure



Figure 1.7 Face-centred cubic structure: (a) unit cell, (b) arrangement of atoms in a (111) close-packed plane, (c) stacking sequence of {111} planes.

Vacancy configurations in fcc



Vacancies in an fcc lattice: (a, b) single vacancy and migration saddle point, (c, d) divacancy and migration saddle point, (e, f) trivacancy and reorientation, (g, h) tetravacancies.

MD simulation of 20keV PKA cascade in single crystal fcc Ni



Close up of defect structure after cascade cooling.

Visualization of the objects produced in MD simulations

e.g. Stacking fault tetrahedra in irradiated copper



Experiments



Cu 0.01 dpa RT weak beam g(6g) g = (200)



Molecular dynamics simulation Pair potential method, 100'000 atoms

Simulations

Schaublin



Multislice technique

 $\Psi(\mathbf{r})\mathbf{j} = [\Psi(\mathbf{r})\mathbf{j}\mathbf{-1} \bullet \mathbf{q}\mathbf{j}] \ge \mathbf{p}\mathbf{j}\mathbf{-}\mathbf{j}\mathbf{+}\mathbf{1}$

 $\Psi(r)j$: Wave function entering slice j+ qj : Function of the transmittance of t slice j,

pj->j+1 : Function of propagation (propagator) from slice j to slice j+1.



J.M. Cowley, A.F. Moodie, Acta Cryst. 10 (1957) 609.

Multislice technique

• Defining the diffraction condition



The Frank loop-type cluster in Al



Interstitial Frank loop simulated TEM images using weak beam g(3.1g), g=(200) at 200 kV in Al for a diameter of about (a) 1.0 nm (8 interstitials), (b) 1.5 nm (19 interstitials) and (c) 2.0 nm (37 interstitials).

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Simulation of SFTs



Table of TEM weak beam images in Cu irradiated at room temperature to 0.046 dpa, showing (**row a**) perfect SFTs, (**row b**) truncated SFTs and (**row c**) groups of intermixed SFT. First column of images (a, b and c) shows corresponding simulated images while second to fourth columns (a1-a4, b1-b4 and c1-c4) show corresponding typical experimental images of those.

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Large loops in ferritic steels

MD simulation. Jaime Marian LLNL USA



F82H, 8.8 dpa, Weak beam g(3.1g) g=(200) 200 kV thickness ~60 nm

Irradiation induced defect clusters in Cu (4.6 10⁻² dpa) and Pd (6.6 10⁻² dpa)







Defect accumulation in technical alloys



Defect cluster Size and Type

the irradiation products are mainly dislocation loops in Pd and stacking fault tetrahedra in Cu





The cluster defect microstructure

- The stacking fault energy plays a role in defining the type of defect cluster formed. In low SFT Cu (45 mJ m⁻²) the majority of defects observed are SFT's. As the SFE increases, SFT are more difficult to form the tendency is to form loops as in Pd (180 mJ m⁻²). But it is not the only controlling factor as indicated by the 304L st. st. (40 mJ.m⁻²).
- While the mean size of SFT's remains constant with dose (low vacancy mobility), loops will grow beyond a certain dose (stainless steels) or temperature (Fe) by accumulation of mobile SIA clusters, developing a broad size distribution.

The cluster defect microstructure

- An almost a linear dependence is found for the density of defects in Cu, Pd or Fe (slope of the log/log plot ~ 0.9). But in Fe, three orders of magnitude higher dose are needed to attain the same defect density.
- Based in particular in the results for SFT's in Cu, the dose dependence of the number density can be taken as an indication that the majority of the defect clusters actually originate from the cascade

Stress-Strain Curves

irradiation induces hardening and embrittlement (apparition of a yield point and a yield region)



Localized deformation in irradiated Cu



Defect-Free Channels



Palladium

6.6 x 10⁻² dpa γ = 80 % **Copper** 3.5 x 10⁻² dpa γ = 15 %

Dislocation channel in Fe12Cr



Defect-free channel in deformed proton-irradiated Fe-12Cr alloy at room temperature to 0.2 dpa. Imaging conditions: BF, $g = \{110\}, ZA = <111>$.





Channel Characteristics

- Channels on {111} planes in fcc and {110} (sometimes {112}) in bcc.
- Interchannel density of defects or density near channel walls is the same as in the as-irradiated crystal: no displacement of defects from the channel by moving dislocations.
- Channel thickness in Cu/Pd: 100-200 nm
- Channel separation (parallel channels): 1µ m

Channel Characteristics

• From measurements of the offset on one channel produced by another channel (in Pd):

450 slip planes per channel

offset per slip plane: 209 nm or 2 dislocations per slip plane. from other observations in Cu/Nb: 1-3 dislocations per slip plane.

- Taking the measured value of the defect size (2 nm), there are 10 slip planes per defect.
- Total shear strain associated with a channel: 0.5-0.7

Change in CRSS versus Dose

different behavior for Pd and Cu



Radiation hardening (I) Source hardening

• Taking for Cu (μ = 55 GPa, b = 0.256 nm) the value of τ_{UY} =50MPa measured in a Cu crystal irradiated with protons to 6.6 10⁻³ dpa, the relation

 $ly^2 = 118 \text{ nm}^3$

is obtained when the measured average value of d=2.05 nm is used.

• The stand-off distance y is unknown and atomistic calculations are needed to get its proper value, but it can be estimated to be of the order of the loop size d. The distance 1 must then be of the order of 10b (3.6 nm) in order to account for the upper yield point, which compares well with that of TEM observations.

Radiation hardening (II) Dispersion hardening

- There is in addition a distribution of loops in the rest of the crystal matrix, at a lower density and larger spacing than those locking the original dislocations.
- The unlocked source dislocation will glide and interact with the distribution of defect clusters present in the matrix of the crystal.
- Defect cluster mean distances: for Cu at 6.6 10⁻³ dpa, the mean distance in the matrix is L = (Nd)^{-1/2} 280 nm, a factor of about one hundred times larger than the value for dislocation locking.

Radiation hardening (II) Dispersion hardening

 The hardening by this defect structure is well represented by the dispersed obstacle model, where the increase of strength, beyond the upper yield point, compared to the unirradiated state, is given by:

 $\Delta \tau = \alpha \mu b (Nd)^{1/2}$

 $\boldsymbol{\alpha}$ is a factor that accounts for the strength of the obstacle.

Radiation hardening (II) Dispersion hardening

- In the irradiated Cu and Pd single crystals there is a linear relation between the measured values of $\Delta \tau$ and $(Nd)^{1/2}$ with a resultant value of $\alpha = 0.1-0.2$, which describes soft obstacles.
- Beyond the yield region, the contribution from dislocation-dislocation interaction to the work hardening is the main component of the flow stress.

Activation volumes in irradiated Cu



The obstacle mean distance controls the hardening



Dispersed Obstacle Hardening Model

Bement 1970; Kojima, Zinkle and Heinisch 1991



A multiscale model for the behavior of irradiated pure fcc metal single cristals

- The recoil energy spectra corresponding to the beam used in the irradiation is calculated.
- A library of cascades produced by recoils of energies typical of this distribution is constructed. The information noted is that of the resulting number of single defects and clusters as well as their types
- This information is fed to an object kMC code together with other information, such as the different reactions between single defects and clusters
- Information on the number of cluster of an observable size (>1 nm) as a function of dose is extracted

Diaz de la Rubia, Zbib, Khraishi, Wirth, Max Victoria and Caturla; Nature **406** (2000) 871

Validation of multiscale modeling of defects produced by cascades: comparison to experimental measurements (LLNL)

Defect concentration in Copper irradiated with Neutrons and Protons compared to kMC simulations





The average size of Vacancy clusters is constant with dose in agreement with experiments. Cluster size ~ 1.7 nm.
Experimental values are ~ 2 nm average cluster size.

Dislocation dynamics simulation

- The time evolution of the motion and interaction of an ensemble of dislocations is followed in a 5µm³ cube of material. It initially contains a density of Frank-Read sources randomly distributed in {111} planes.
- Dislocations are discretized into straight line segments of mixed character.
- To ensure continuity of dislocation lines across the boundaries, reflection boundary conditions are used.

Dislocation dynamics simulation

- The Peach-Koehler force F acting on a dislocation segment is calculated from the stress fields of (a) neighboring segments, (b) all other dislocation segments, (c) all defect clusters and (d) the applied stress.
- The result is used to advance the dislocation segment based on linear mobility $v_{gi} = M_{gi}F_{gi}$ (M_{gi} : dislocation mobility, F_{gi} : glide component of Peach-Koehler force minus the Peierls friction.
- Segments about to experience short range interactions are identified. Reactions might result in formation of junctions, jogs, dipoles.

Dislocation dynamics simulation

 Cross-slip is described as an activated process with probability P given by:

P=α Ω_I δt exp [-(Ω–τA)/kT] for Ω_I = C_t π/ L

- Defects (SFT's or Frank sessile interstitial loops) are mapped into the DD box in densities in accord to those produced by a particilar fluence and temperature.
- Decorated F-R sources are also introduced.
- Detailed atomistic modeling of the dislocation-defect interaction are performed in MD simulations

Dislocation-SFT interaction (From B. Wirth)





Figure 2 -- <111> (top) and <110> (bottom) projections of high energy atoms showing the motion of two Shockley partials on their {111} glide plane and interaction with an overlapping SFT at a) 7.2, b) 16.0 and c) 16.8 ps after application of a shear stress.





The interaction of dislocations with SFT's

In situ TEM observations in irradiated Cu (Yao and Schaublin)









Summary

The results of irradiations in fcc Cu, Pd and 304L austenitic stainless steel and with either fission neutrons or 590 MeV protons indicate that:

 A high density (10²²-10²⁴ m⁻³) of defect clusters is found. The majority of clusters are SFT's in Cu while in Pd and Fe they are interstitial loops, showing that for low stacking fault energy metals (Cu), SFT's form, while loops are the main component of the microstructure for high SFE metals Pd and Fe. Austenitic stainless steels are an exception to this trend in that the SFE is low but loops are formed.